

FAIRCHILD SEMICONDUCTOR®

FDS6910

Dual N-Channel Logic Level PowerTrench[®] MOSFET

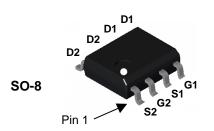
General Description

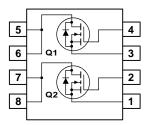
These N-Channel Logic Level MOSFETs are produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

Features

- $\mbox{ } \bullet \mbox{ } 7.5 \mbox{ A}, \mbox{ } 30 \mbox{ V}. \qquad R_{\text{DS}(\text{ON})} = 13 \mbox{ } m\Omega \ @ \mbox{ } V_{\text{GS}} = 10 \mbox{ } V \\ R_{\text{DS}(\text{ON})} = 17 \mbox{ } m\Omega \ @ \mbox{ } V_{\text{GS}} = 4.5 \mbox{ } V \\ \mbox{ } \end{array}$
- Fast switching speed
- Low gate charge
- High performance trench technology for extremely low $R_{\text{DS}(\text{ON})}$
- High power and current handling capability





Absolute Maximum Ratings TA=25°C unless otherwise noted

Symbol		Parameter		Ratings	Units
V _{DSS}	Drain-Sourc	e Voltage		30	V
V _{GSS}	Gate-Sourc	Gate-Source Voltage		± 20	V
I _D	Drain Curre	nt – Continuous	(Note 1a)	7.5	A
		– Pulsed		20	
PD	Power Dissi	pation for Single Operation	(Note 1a)	1.6	W
			(Note 1b)	1.0	
			(Note 1c)	0.9	
T _J , T _{STG}	Operating and Storage Junction Temperature Range			-55 to +150	°C
Therma	I Charac	teristics			
R _{eJA}	Thermal Re	I Resistance, Junction-to-Ambient (Note 1a)		78	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Note 1)		(Note 1)	40	
Packag	e Marking	g and Ordering l	nformation		
	e Marking	g and Ordering II Device	nformation Reel Size	Tape width	Quantity

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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics					
BV _{DSS}	Drain–Source Breakdown Voltage	$V_{GS} = 0 V$, $I_D = 250 \mu A$	30			V
<u>ΔBVdss</u> ΔTj	Breakdown Voltage Temperature Coefficient	I_D = 250 µA, Referenced to 25°C		28		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current				1 10	μA
I _{GSS}	Gate–Source Leakage	$V_{GS}=\pm 20~V,~V_{DS}=0~V$			±100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	1	1.8	3	V
<u>ΔVgs(th)</u> ΔTJ	Gate Threshold Voltage Temperature Coefficient	I_D = 250 µA, Referenced to 25°C		-4.7		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$ \begin{array}{l} V_{\rm GS} = 10 \ V, I_{\rm D} = 7.5 \ A \\ V_{\rm GS} = 4.5 \ V, I_{\rm D} = 6.5 \ A \\ V_{\rm GS} = 10 \ V, \ I_{\rm D} = 7.5 \ A, T_{\rm J} = 125^{\circ}C \end{array} $		10.6 13 14.5	13 17 20	mΩ
I _{D(on)}	On–State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 5 \text{ V}$	20			А
g _{FS}	Forward Transconductance	$V_{DS} = 5 V$, $I_{D} = 7.5 A$		36		S
Dynamic	Characteristics	•				
Ciss	Input Capacitance	$V_{DS} = 15 V$, $V_{GS} = 0 V$,		1130		pF
Coss	Output Capacitance	f = 1.0 MHz		300		pF
C _{rss}	Reverse Transfer Capacitance	7		100		pF
R _G	Gate Resistance	$V_{GS} = 15 \text{ mV}, \text{ f} = 1.0 \text{ MHz}$		2.4		Ω
	g Characteristics (Note 2)					
Switchin		$V_{DD} = 15 V$, $I_D = 1 A$,		9	18	ns
	Turn–On Delay Time					
t _{d(on)}	Turn–On Delay Time Turn–On Rise Time	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$		5	10	ns
t _{d(on)} t _r	,			5 26	10 42	ns ns
t _{d(on)} t _r t _{d(off)}	Turn–On Rise Time			-		
t _{d(on)} t _r t _{d(off)} t _f	Turn-On Rise Time Turn-Off Delay Time			26	42	ns
t _{d(on)} t _r t _{d(off)} t _f Q _{g(TOT)}	Turn–On Rise Time Turn–Off Delay Time Turn–Off Fall Time			26 7	42 14	ns ns
Switchin t _{d(on)} tr t _{d(off)} t _f Q _{g(TOT)} Q _g Q _{gs}	Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge at Vgs=10V	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$		26 7 17	42 14 24	ns ns nC

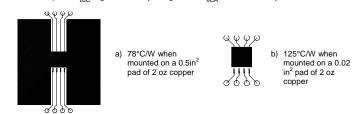
FDS6910 Rev B(W)

				oted		
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-Sc	urce Diode Characteristics and M	laximum Ratings				
ls	Maximum Continuous Drain–Source Diode Forward Current 1.3 A				А	
V _{SD}	Drain–Source Diode Forward V	$_{GS} = 0 V$, $I_{S} = 1.3 A$ (Note 2)			1.2	V
VSD	Voltage					
v _{sD}	Voltage	$= 7.5 \text{ A}, d_{iF}/d_t = 100 \text{ A}/\mu\text{s}$		24		nS

Notes:

1. R_{0JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $\rm R_{\theta JC}$ is guaranteed by design while $\rm R_{\theta CA}$ is determined by the user's board design.

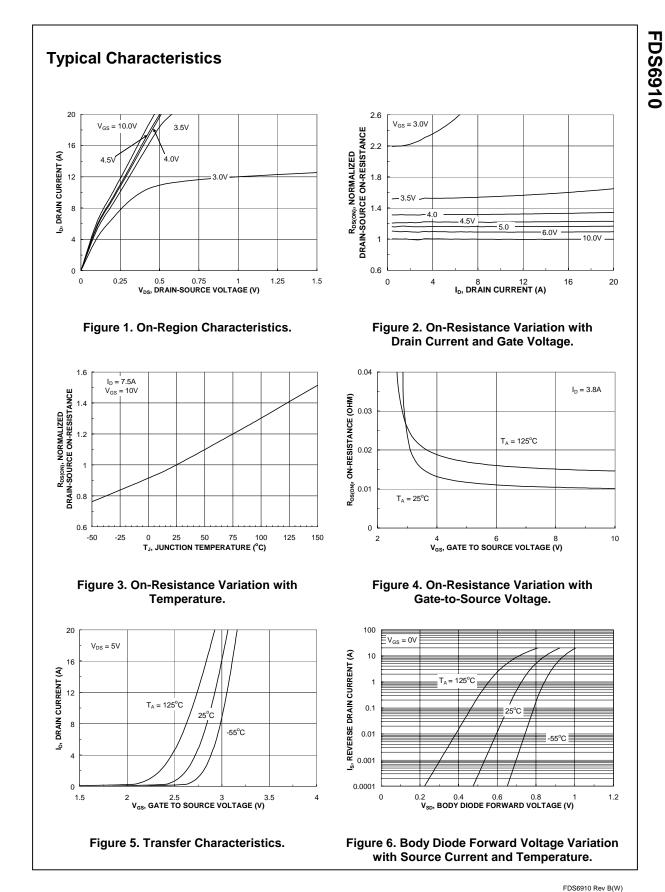
c) 135°C/W when mounted on a minimum mounting pad.



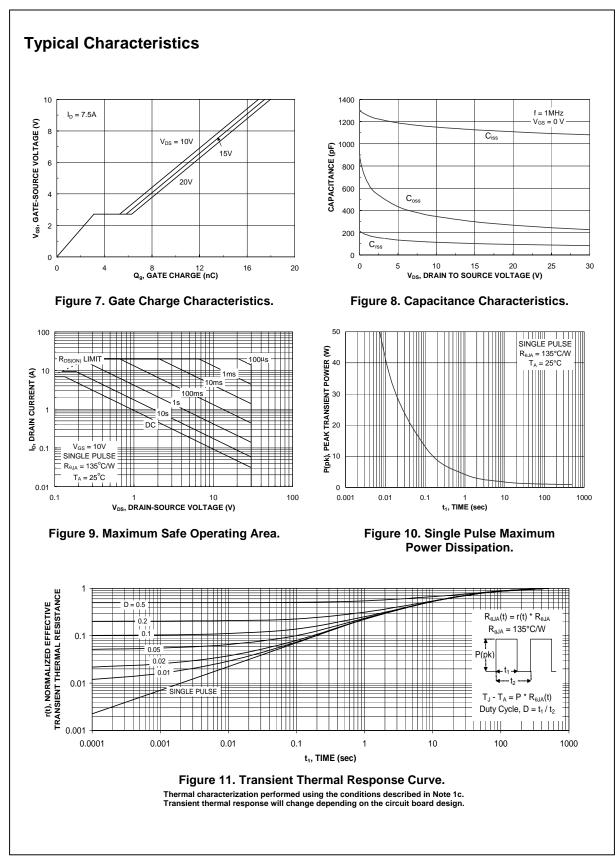
Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%

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FD56910 Rev B(V



FDS6910

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	-	Rev. I1: